ESD PROTECTED, HIGH-SPEED USB 2.0 (480-Mbps)
1:2 MULTIPLEXER/DEMULTIPLEXER SWITCH WITH SINGLE ENABLE

Check for Samples: TS3USB30E

## FEATURES

- **V_{CC} Operation at 3 V to 4.3 V**
- **1.8-V Compatible Control-Pin Inputs**
- **I_{OFF} Supports Partial Power-Down-Mode Operation**
  - **D+/D− Pins Tolerate up to 5.25V**
- **r_{ON} = 10 Ω Max**
- **Δr_{ON} = 0.35 Ω Typ**
- **$C_{io(ON)}$ = 7.5 pF Typ**
- **Low Power Consumption (1 μA Max)**
- **−3 dB Bandwidth = 900 MHz Typ**
- **Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II** [1]
- **ESD Performance Tested Per JESD 22**
  - **8000-V Human-Body Model (A114-B, Class II)**
  - **1000-V Charged-Device Model (C101)**
- **ESD Performance I/O Port to GND** [2]
  - **15000-V Human-Body Model**
- **Packaged in 10-pin TQFN (1.4 mm × 1.8 mm)**

APPLICATIONS

- **Routes Signals for USB 1.0, 1.1, and 2.0**

(1) Except $\overline{OE}$ and S inputs
(2) High-voltage HBM is performed in addition to the standard HBM testing (A114-B, Class II) and applies to I/O ports tested with respect to GND only.

**RSW PACKAGE
(TOP VIEW)**

**RSW PACKAGE
(BOTTOM VIEW)**

**DGS PACKAGE
(TOP VIEW)**
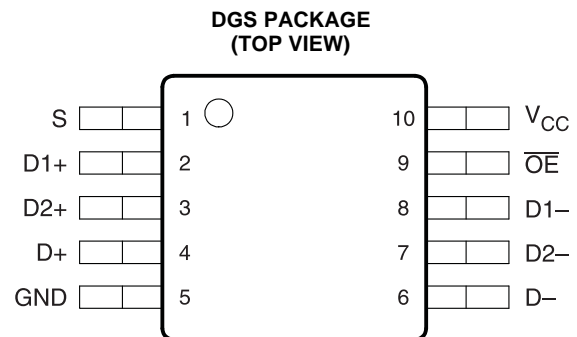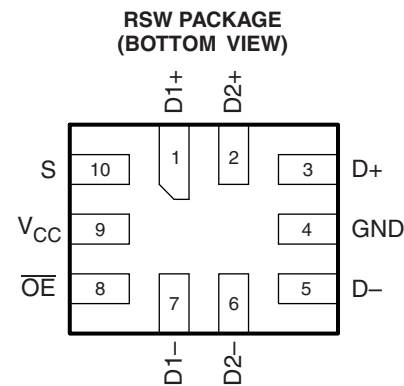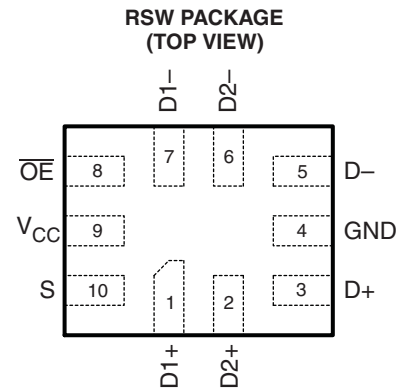
![Warning symbol] Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

TS3USB30E

DESCRIPTION/ORDERING INFORMATION

The TS3USB30E is a high-bandwidth switch specially designed for the switching of high-speed USB 2.0 signals in handset and consumer applications, such as cell phones, digital cameras, and notebooks with hubs or controllers with limited USB I/Os. The wide bandwidth (900 MHz) of this switch allows signals to pass with minimum edge and phase distortion. The device multiplexes differential outputs from a USB host device to one of two corresponding outputs. The switch is bidirectional and offers little or no attenuation of the high-speed signals at the outputs. It is designed for low bit-to-bit skew and high channel-to-channel noise isolation, and is compatible with various standards, such as high-speed USB 2.0 (480 Mbps).

The TS3USB30E integrates ESD protection cells on all pins, is available in a tiny μQFN package (1.8 mm × 1.4 mm), a DGS package, and is characterized over the free air temperature range of –40°C to 85°C.

ORDERING INFORMATION

T_A	PACKAGE[1] [2]		ORDERABLE PART NUMBER	TOP-SIDE MARKING[3]
–40°C to 85°C	UQFN – RSW	Tape and reel	TS3USB30ERSWR	LY_
	VSSOP – DGS	Tape and reel	TS3USB30EDGSR	L6R

(1) Package drawings, thermal data, and symbolization are available at www.ti.com/packaging.
(2) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.
(3) RSW: The actual top-side marking has one additional character that designates the assembly/test site.

PIN DESCRIPTION

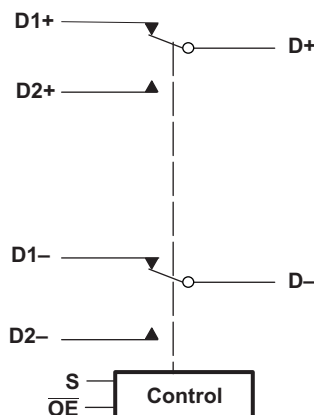| NAME	DESCRIPTION
$\overline{OE}$	Bus-switch enable
S	Select input
D+, D–, Dn+, Dn–	Data ports

TRUTH TABLE

S	$\overline{OE}$	FUNCTION
X	H	Disconnect
L	L	D = D1
H	L	D = D2

BLOCK DIAGRAM

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Product Folder Link(s): *TS3USB30E*

ABSOLUTE MAXIMUM RATINGS[1] [2]

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
V_{CC}	Supply voltage range		−0.5	7	V
V_{IN}	Control input voltage range[3]		−0.5	7	V
$V_{I/O}$	Switch I/O voltage range[3] [4]	Dn+, Dn−	−0.5	V_{CC} + 0.3	V
		D+, D− when V_{CC} > 0	−0.5	V_{CC} + 0.3	
		D+, D− when V_{CC} = 0	−0.5	5.25	
I_{IK}	Control input clamp current	V_{IN} < 0		−50	mA
$I_{I/OK}$	I/O port clamp current	$V_{I/O}$ < 0		−50	mA
$I_{I/O}$	ON-state switch current[5]			±64	mA
	Continuous current through V_{CC} or GND			±100	mA
T_{stg}	Storage temperature range		−65	150	°C

(1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
(2) All voltages are with respect to ground, unless otherwise specified.
(3) The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
(4) V_I and V_O are used to denote specific conditions for $V_{I/O}$.
(5) I_I and I_O are used to denote specific conditions for $I_{I/O}$.

PACKAGE THERMAL IMPEDANCE[1]

			TYP	UNIT
θ_{JA}	Package thermal impedance	DGS package	56.5	°C/W
		RSW package	175	

(1) The package thermal impedance is calculated in accordance with JESD 51-7.

RECOMMENDED OPERATING CONDITIONS[1]

			MIN	MAX	UNIT
V_{CC}	Supply voltage		3	4.3	V
V_{IH}	High-level control input voltage	V_{CC} = 3 V to 3.6 V	1.3		V
		V_{CC} = 4.3 V	1.7		
V_{IL}	Low-level control input voltage	V_{CC} = 3 V to 3.6 V		0.5	V
		V_{CC} = 4.3 V		0.7	
$V_{I/O}$	Data input/output voltage		0	V_{CC}	V
T_A	Operating free-air temperature		−40	85	°C

(1) All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

ELECTRICAL CHARACTERISTICS[1]

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS			MIN	TYP[2]	MAX	UNIT
V_{IK}		V_{CC} = 3 V,	I_I = −18 mA				−1.2	V
I_{IN}	Control inputs	V_{CC} = 4.3 V, 0 V,	V_{IN} = 0 to 4.3 V				±1	μA
I_{OZ} [3]		V_{CC} = 4.3 V, V_I = 0,	V_O = 0 to 3.6 V, Switch OFF				±1	μA
I_{OFF}	D+ and D−	V_{CC} = 0 V, V_I = 0,	V_O = 0 to 4.3 V, V_{IN} = V_{CC} or GND				±2	μA
I_{CC}		V_{CC} = 4.3 V,	$I_{I/O}$ = 0,	Switch ON or OFF			1	μA
ΔI_{CC} [4]	Control inputs	V_{CC} = 4.3 V,	V_{IN} = 2.6 V				10	μA
C_{in}	Control inputs	V_{CC} = 0 V,	V_{IN} = V_{CC} or GND			1		pF
$C_{io(OFF)}$		V_{CC} = 3.3 V,	$V_{I/O}$ = 3.3 V or 0,	Switch OFF		2		pF
$C_{io(ON)}$		V_{CC} = 3.3 V,	$V_{I/O}$ = 3.3 V or 0,	Switch ON		7.5		pF
r_{on} [5]		V_{CC} = 3 V,	V_I = 0.4,	I_O = −8 mA		6	10	Ω
Δr_{on}		V_{CC} = 3 V,	V_I = 0.4,	I_O = −8 mA		0.35		Ω
$r_{on(flat)}$		V_{CC} = 3 V,	V_I = 0 V or 1 V,	I_O = −8 mA		2		Ω

(1) V_{IN} and I_{IN} refer to control inputs. V_I, V_O, I_I, and I_O refer to data pins.
(2) All typical values are at V_{CC} = 3.3 V (unless otherwise noted), T_A = 25°C.
(3) For I/O ports, the parameter I_{OZ} includes the input leakage current.
(4) This is the increase in supply current for each input that is at the specified TTL voltage level, rather than V_{CC} or GND.
(5) Measured by the voltage drop between the A and B terminals at the indicated current through the switch. ON-state resistance is determined by the lower of the voltages of the two (A or B) terminals.

Product Folder Link(s): *TS3USB30E*

DYNAMIC ELECTRICAL CHARACTERISTICS

over operating range, T_A = –40°C to 85°C, V_{CC} = 3.3 V ± 10%, GND = 0 V

PARAMETER		TEST CONDITIONS	TYP[1]	UNIT
X_{TALK}	Crosstalk	R_L = 50 Ω, f = 240 MHz, See Figure 10	–54	dB
O_{ISO}	OFF isolation	R_L = 50 Ω, f = 240 MHz, See Figure 9	–40	dB
BW	Bandwidth (–3 dB)	R_L = 50 Ω, C_L = 5 pF, See Figure 11	900	MHz

(1) For Max or Min conditions, use the appropriate value specified under Electrical Characteristics for the applicable device type.

SWITCHING CHARACTERISTICS

over operating range, T_A = –40°C to 85°C, V_{CC} = 3.3 V ± 10%, GND = 0 V

PARAMETER		TEST CONDITIONS	MIN	TYP[1]	MAX	UNIT
t_{pd}	Propagation delay[2] [3]	R_L = 50 Ω, C_L = 5 pF, See Figure 12		0.25		ns
t_{ON}	Line enable time, SEL to D, nD	R_L = 50 Ω, C_L = 5 pF, See Figure 8			30	ns
t_{OFF}	Line disable time, SEL to D, nD	R_L = 50 Ω, C_L = 5 pF, See Figure 8			25	ns
t_{ON}	Line enable time, $\overline{OE}$ to D, nD	R_L = 50 Ω, C_L = 5 pF, See Figure 8			30	ns
t_{OFF}	Line disable time, $\overline{OE}$ to D, nD	R_L = 50 Ω, C_L = 5 pF, See Figure 8			25	ns
$t_{SK(O)}$	Output skew between center port to any other port[2]	R_L = 50 Ω, C_L = 5 pF, See Figure 13			50	ps
$t_{SK(P)}$	Skew between opposite transitions of the same output (t_{PHL} – t_{PLH})[2]	R_L = 50 Ω, C_L = 5 pF, See Figure 13			20	ps
t_J	Total jitter[2]	R_L = 50 Ω, C_L = 5 pF, t_R = t_F = 500 ps at 480 Mbps (PRBS = 2^{15} – 1)			20	ps

(1) For Max or Min conditions, use the appropriate value specified under Electrical Characteristics for the applicable device type.
(2) Specified by design
(3) The bus switch contributes no propagational delay other than the RC delay of the on resistance of the switch and the load capacitance. The time constant for the switch alone is of the order of 0.25 ns for 10-pF load. Since this time constant is much smaller than the rise/fall times of typical driving signals, it adds very little propagational delay to the system. Propagational delay of the bus switch, when used in a system, is determined by the driving circuit on the driving side of the switch and its interactions with the load on the driven side.
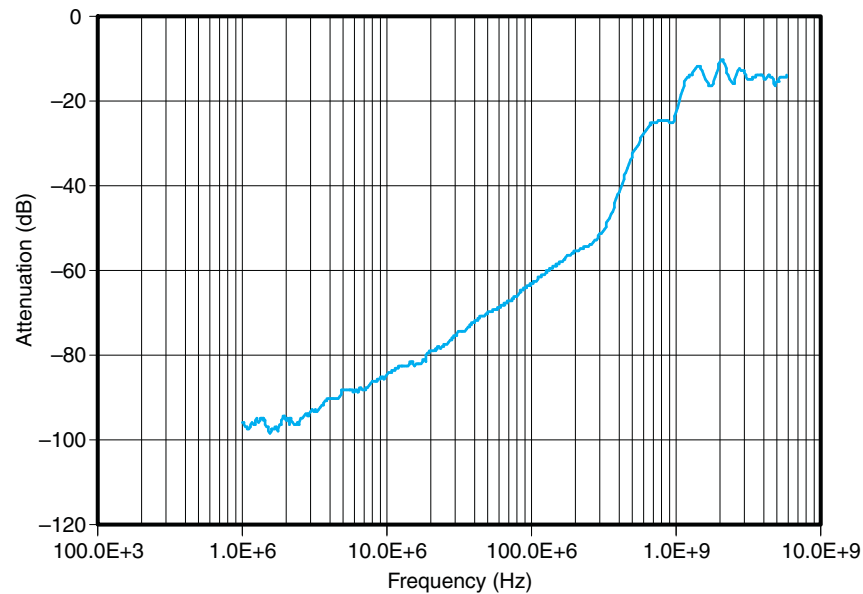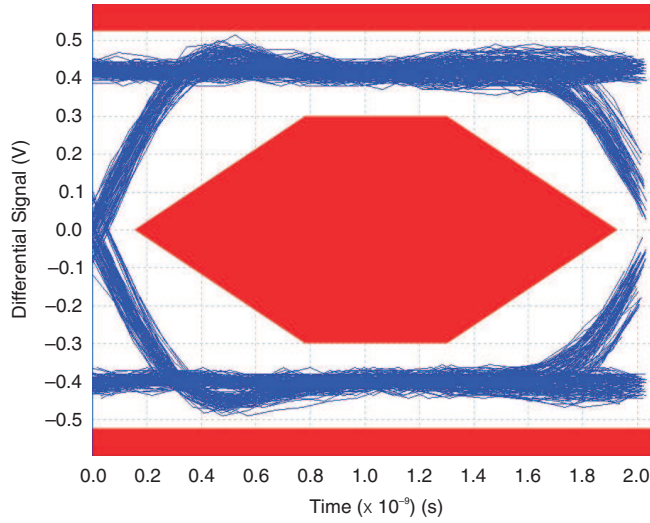
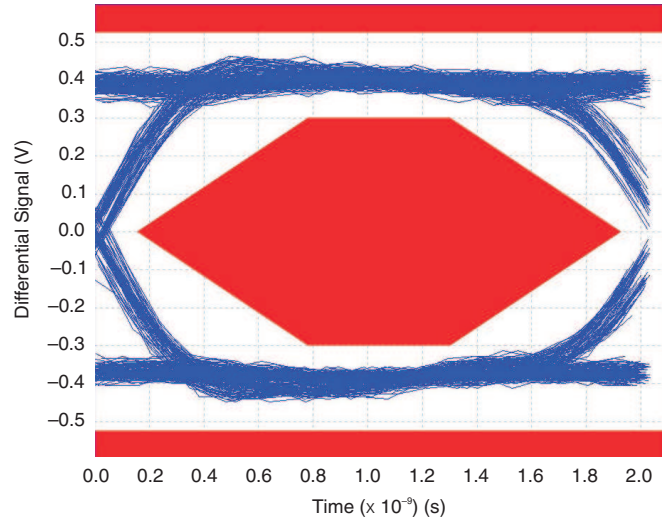## APPLICATION INFORMATION
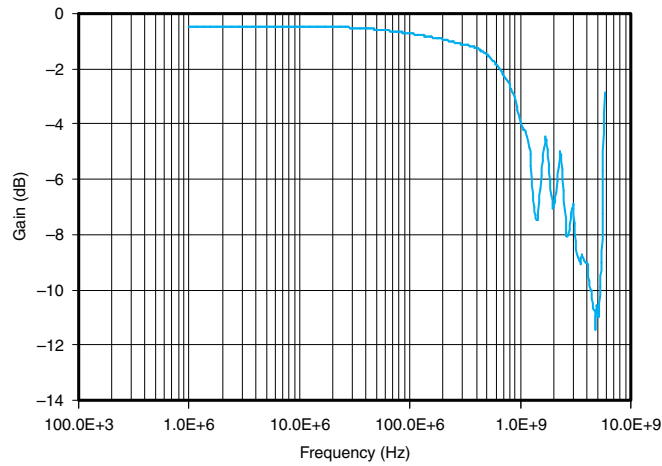
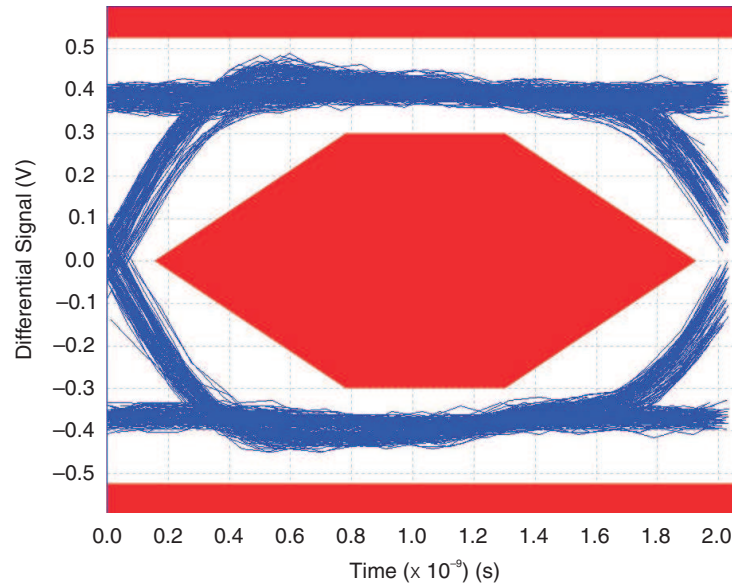**Figure 1. Gain vs Frequency**
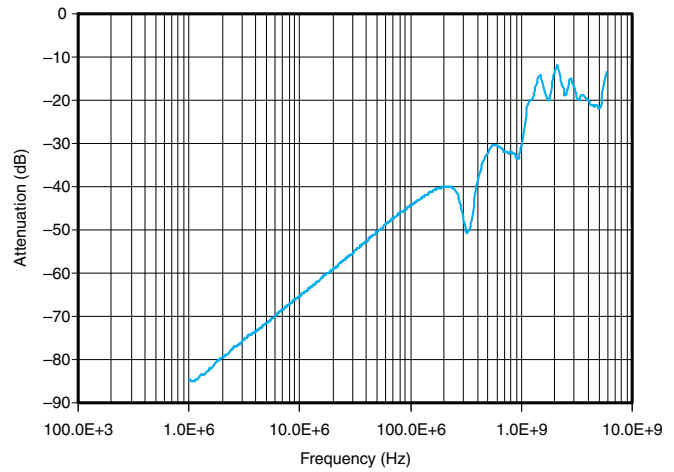
Figure 2. OFF Isolation

Figure 3. Crosstalk

Product Folder Link(s): *TS3USB30E*

Figure 4. Eye Pattern: 480-Mbps USB Signal With No Switch (Through Path)

Figure 5. Eye Pattern: 480-Mbps USB Signal With Switch NC Path

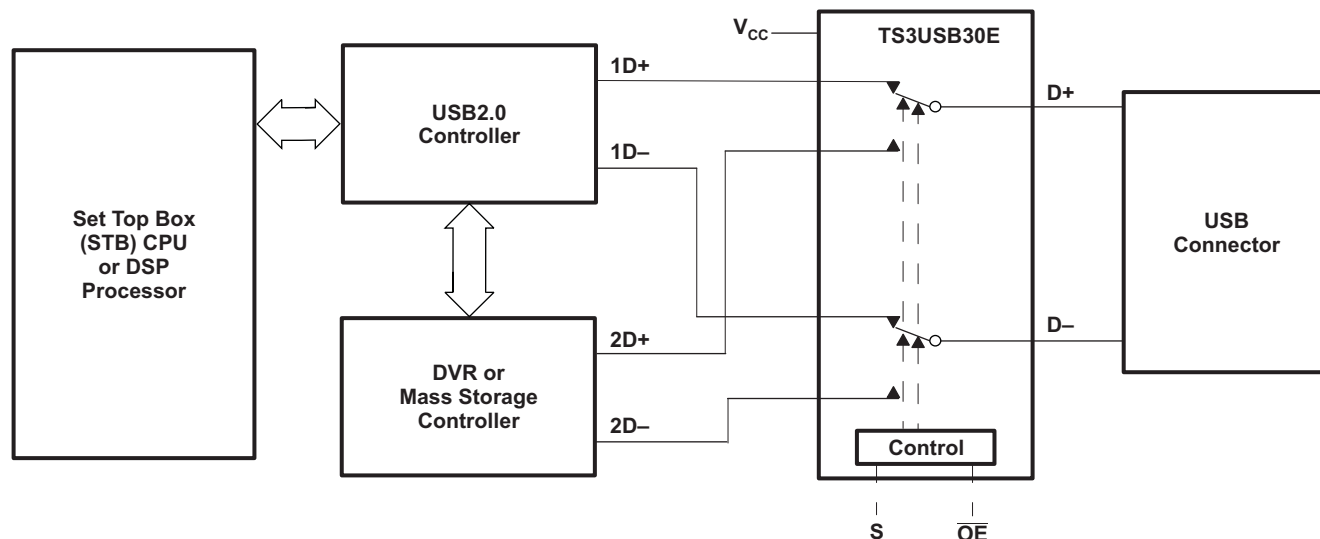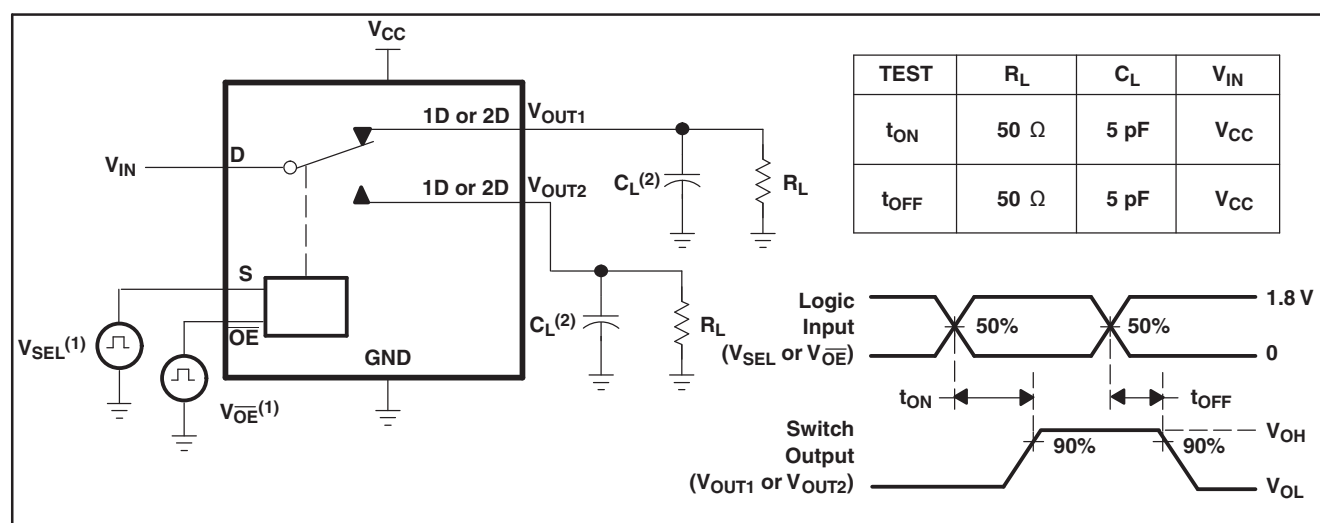**Figure 6. Eye Pattern: 480-Mbps USB Signal With Switch NO Path**

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Figure 7. Application Diagram

PARAMETER MEASUREMENT INFORMATION

TEST	R_L	C_L	V_{IN}
t_{ON}	50 Ω	5 pF	V_{CC}
t_{OFF}	50 Ω	5 pF	V_{CC}

(1) All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r < 5 ns, t_f < 5 ns.

(2) C_L includes probe and jig capacitance.

Figure 8. Turn-On (t_{ON}) and Turn-Off Time (t_{OFF})

Product Folder Link(s): *TS3USB30E*

PARAMETER MEASUREMENT INFORMATION (continued)
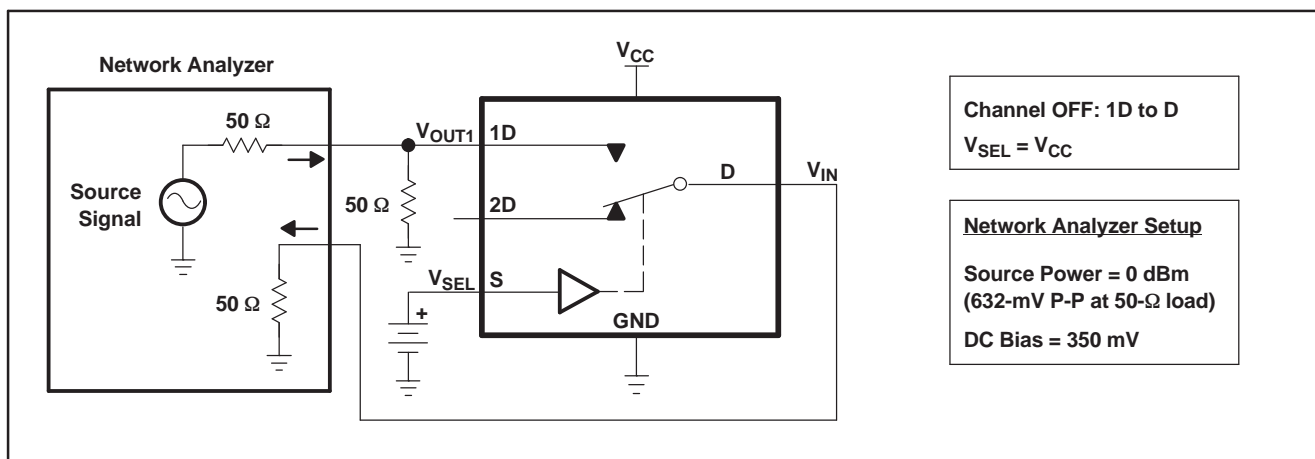
Figure 9. OFF Isolation (O$_{ISO}$)
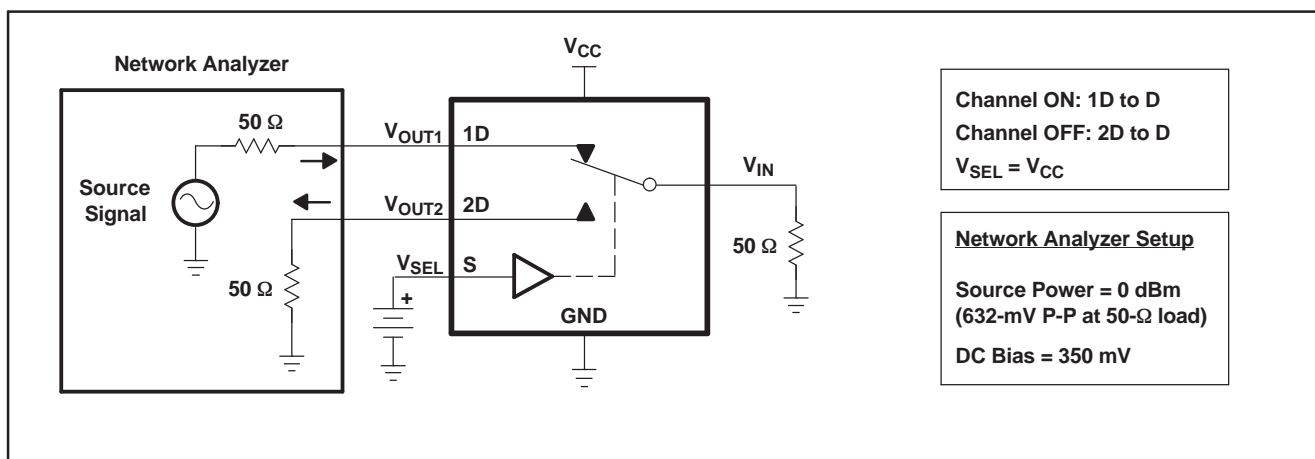
Figure 10. Crosstalk (X$_{TALK}$)
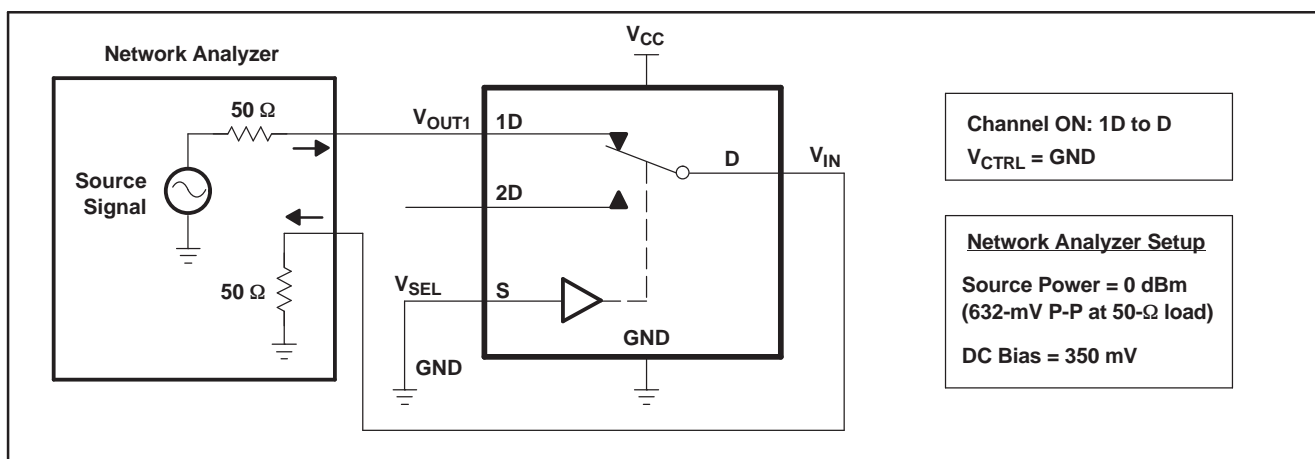
Figure 11. Bandwidth (BW)

PARAMETER MEASUREMENT INFORMATION (continued)
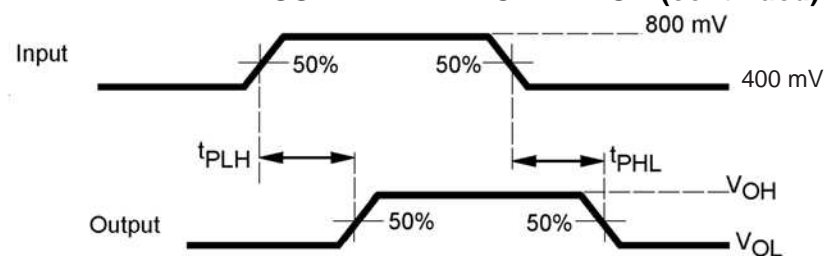
Figure 12. Propagation Delay

$$t_{SK(P)} = |\, t_{PHL} - t_{PLH}\,|$$

Pulse Skew $t_{SK(P)}$

$$t_{SK(O)} = |t_{PLH1} - t_{PLH2}|\ \text{or}\ |\, t_{PHL1} - t_{PHL2}\,|$$
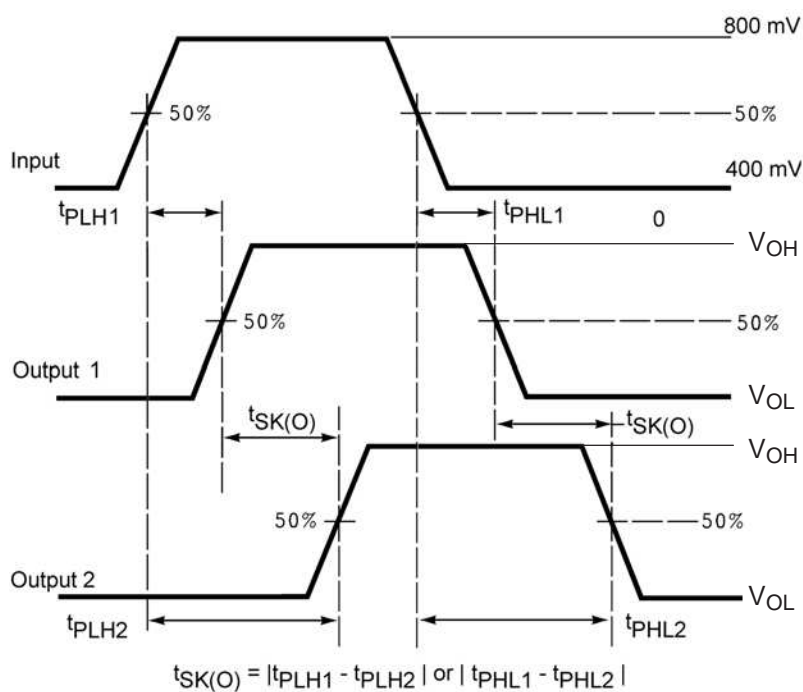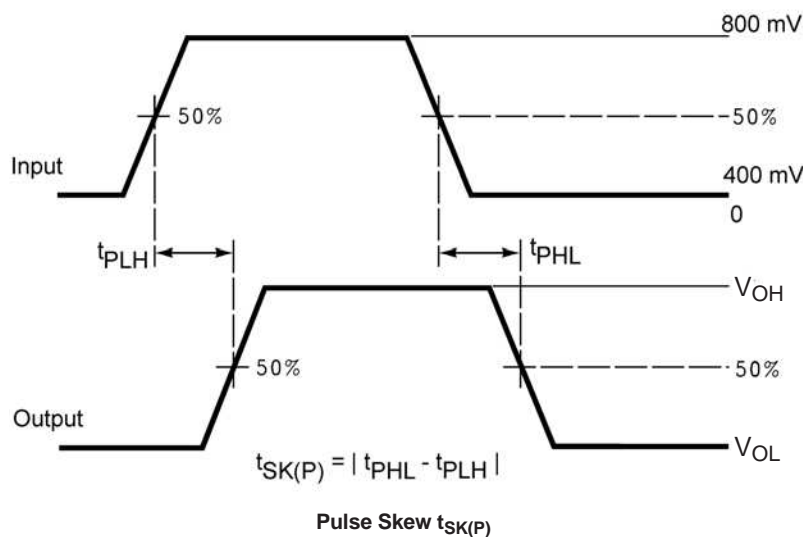
Output Skew $t_{SK(P)}$

Figure 13. Skew Test

Product Folder Link(s): TS3USB30E

PARAMETER MEASUREMENT INFORMATION (continued)

Channel ON

$$r_{on} = \frac{V_{IN} - V_{OUT2} \text{ or } V_{OUT1}}{I_{IN}} \Omega$$

$V_{SEL} = V_{IH} \text{ or } V_{IL}$
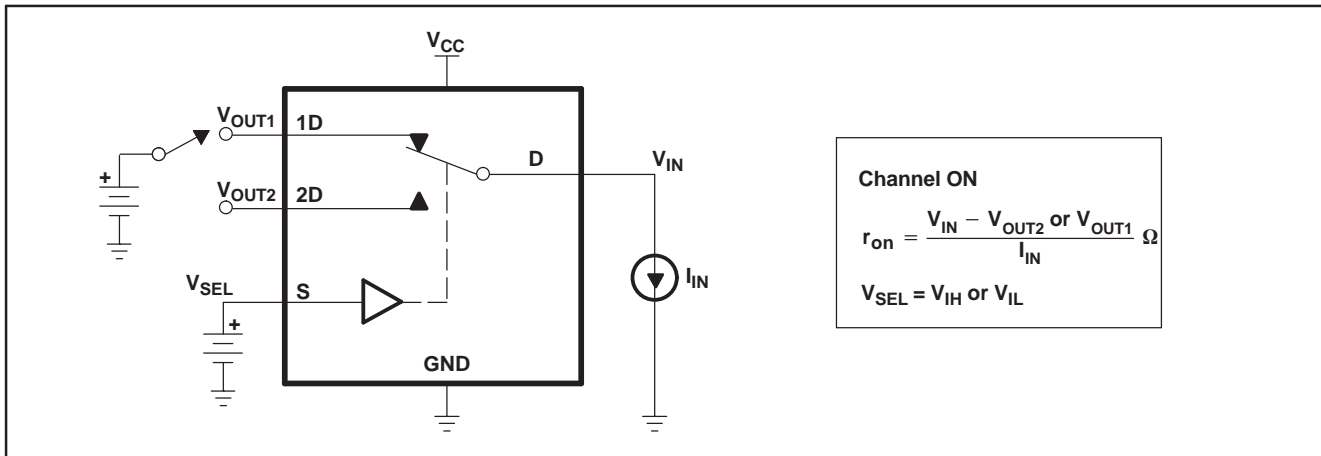
Figure 14. ON-State Resistance (r_{on})

OFF-State Leakage Current
Channel OFF
$V_{SEL} = V_{IH} \text{ or } V_{IL}$
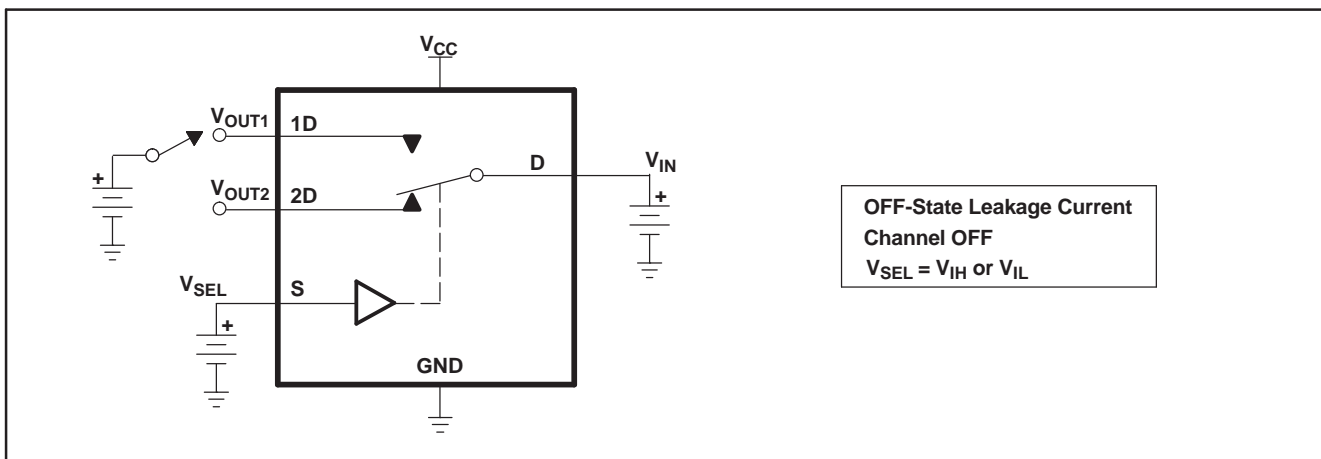
Figure 15. OFF-State Leakage Current

$V_{BIAS} = V_{CC} \text{ or } GND$

$V_{SEL} = V_{CC} \text{ or } GND$

Capacitance is measured at 1D, 2D, D, and S inputs during ON and OFF conditions.

Figure 16. Capacitance
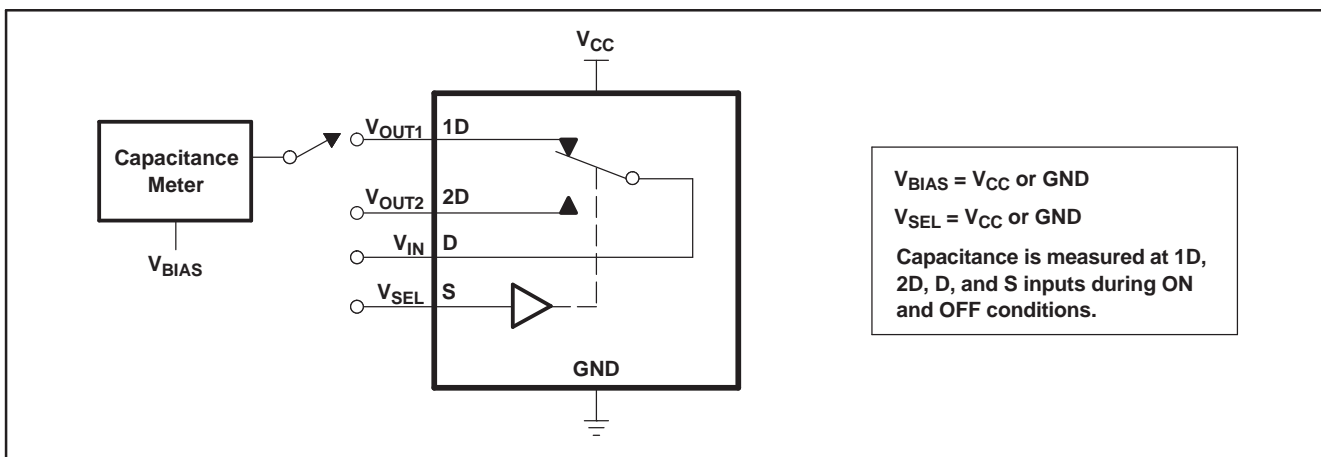
Product Folder Link(s): *TS3USB30E*

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/ Ball Finish	MSL Peak Temp (3)	Samples (Requires Login)
TS3USB30EDGSR	ACTIVE	MSOP	DGS	10	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
TS3USB30ERSWR	ACTIVE	UQFN	RSW	10	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	

(1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.
TBD: The Pb-Free/Green conversion plan has not been defined.
Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.
Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.
Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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PACKAGE MATERIALS INFORMATION

TAPE AND REEL INFORMATION

REEL DIMENSIONS

TAPE DIMENSIONS

A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE
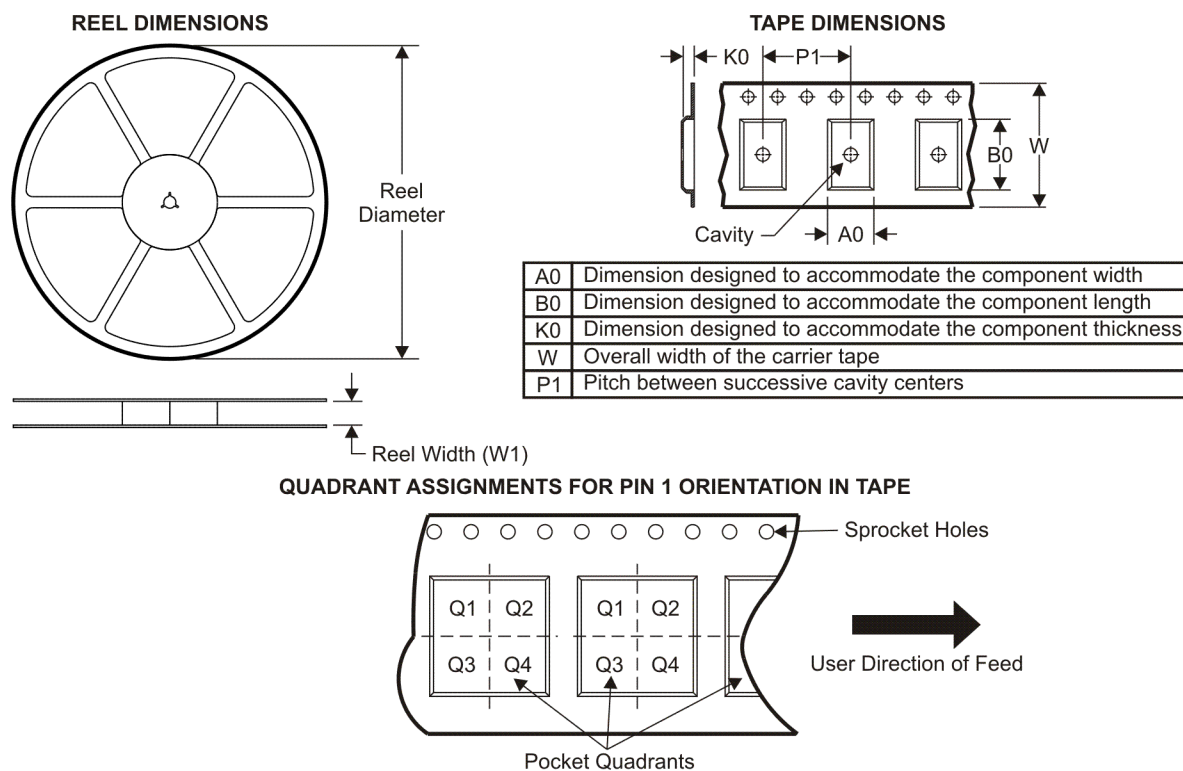
*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TS3USB30EDGSR	MSOP	DGS	10	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
TS3USB30ERSWR	UQFN	RSW	10	3000	179.0	8.4	1.7	2.1	0.7	4.0	8.0	Q1

PACKAGE MATERIALS INFORMATION

TAPE AND REEL BOX DIMENSIONS

*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TS3USB30EDGSR	MSOP	DGS	10	2500	358.0	335.0	35.0
TS3USB30ERSWR	UQFN	RSW	10	3000	203.0	203.0	35.0

DGS (S−PDSO−G10) PLASTIC SMALL−OUTLINE PACKAGE

0,50

10

6

0,27 / 0,17 ⊕ 0,08 Ⓜ

3,10 / 2,90

5,05 / 4,75

1

5

3,10 / 2,90

1,10 MAX

0,15 / 0,05

0,23 / 0,13

Gauge Plane

0°−8°

0,25

0,70 / 0,40

Seating Plane

◠ 0,10

4073272/C 02/04

NOTES: A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Body dimensions do not include mold flash or protrusion.
D. Falls within JEDEC MO−187 variation BA.
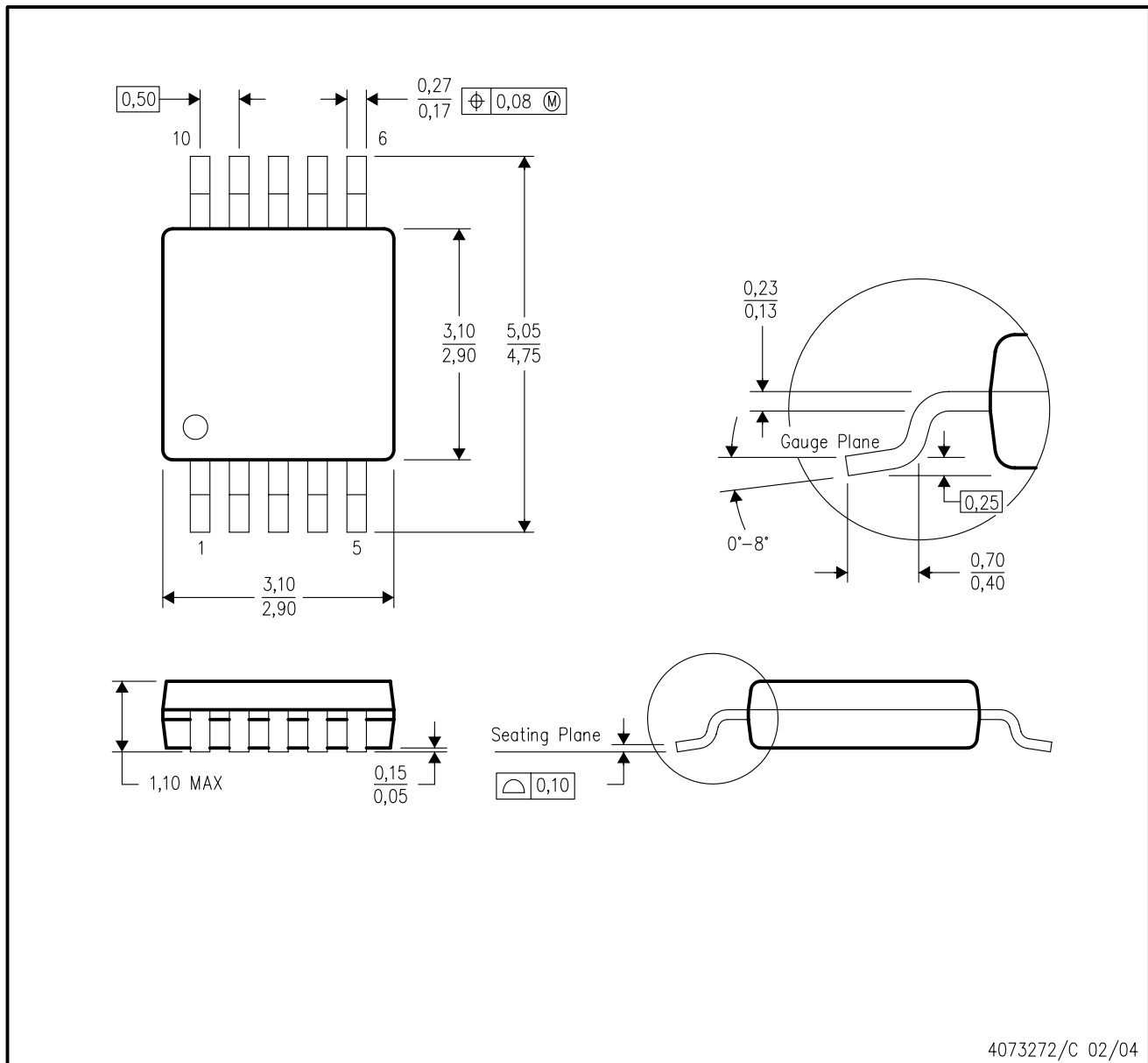
RSW (R–PUQFN–N10)   PLASTIC QUAD FLATPACK NO–LEAD

1,85
1,75 [A]

[B]

1,45
1,35

Pin 1 Index Area

0,55
0,45

0,13 Nominal
Lead Frame

Seating Plane

0,05 C

0,05
0,00
Seating Height

0,40

0,20

0,55
0,45

0,80

Pin 1 Identifier
0,10 X 45°

9X 0,45
0,35

10X 0,25
0,15

0,07 (M) C A B
0,05 (M) C

Bottom View
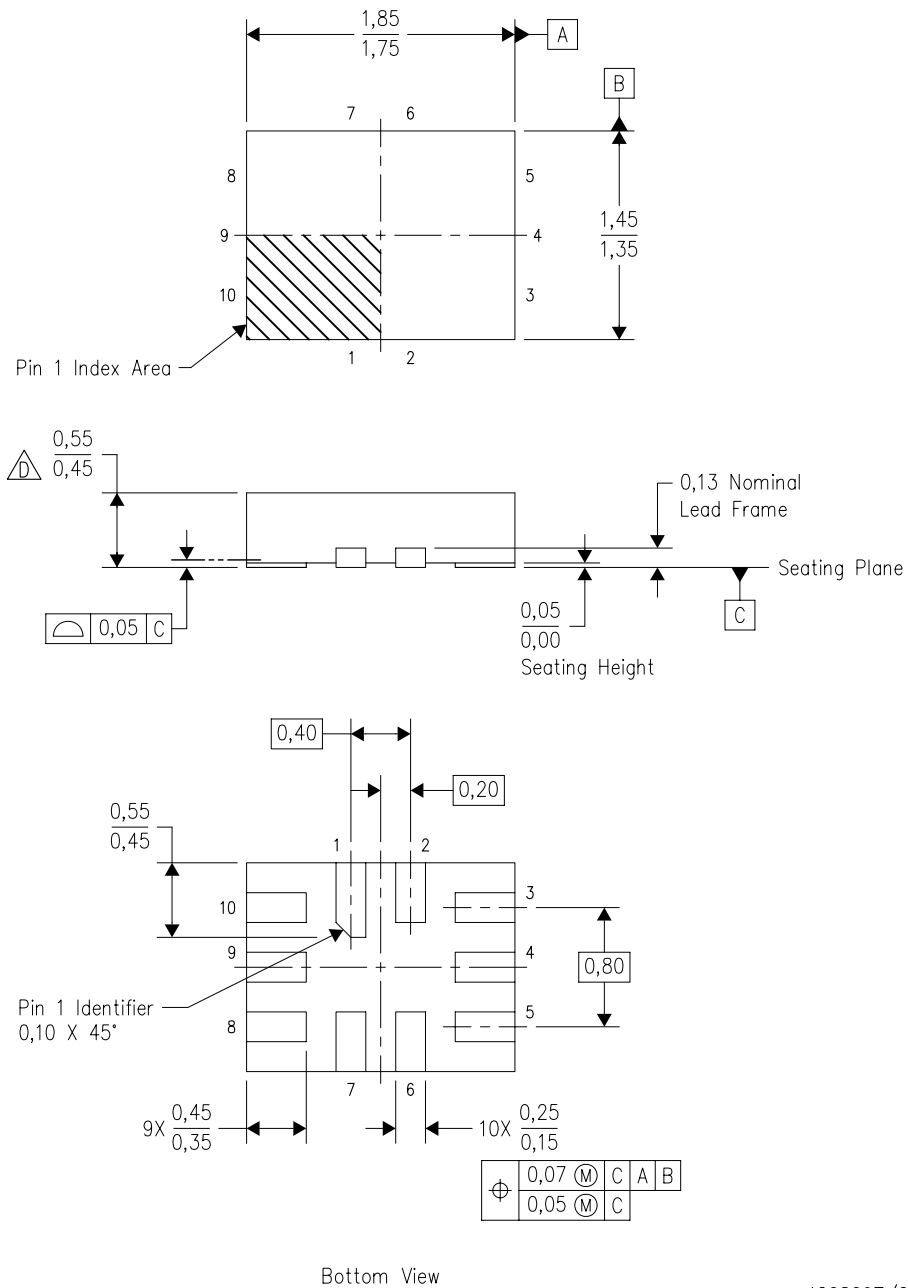
4208097/C 07/2008

NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M–1994.
        B. This drawing is subject to change without notice.
        C. QFN (Quad Flatpack No–lead) package configuration.
        D. This package complies to JEDEC MO–288 variation UDEE, except minimum package height.

TEXAS
INSTRUMENTS
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RSW (R−PQFP−N10)

Land

Stencil

Non Solder Mask Defined Pad

Pin 1 ID

Example Solder Mask Opening
(Note E)

Example Pad Geometry
(Note C)

Scale 2X
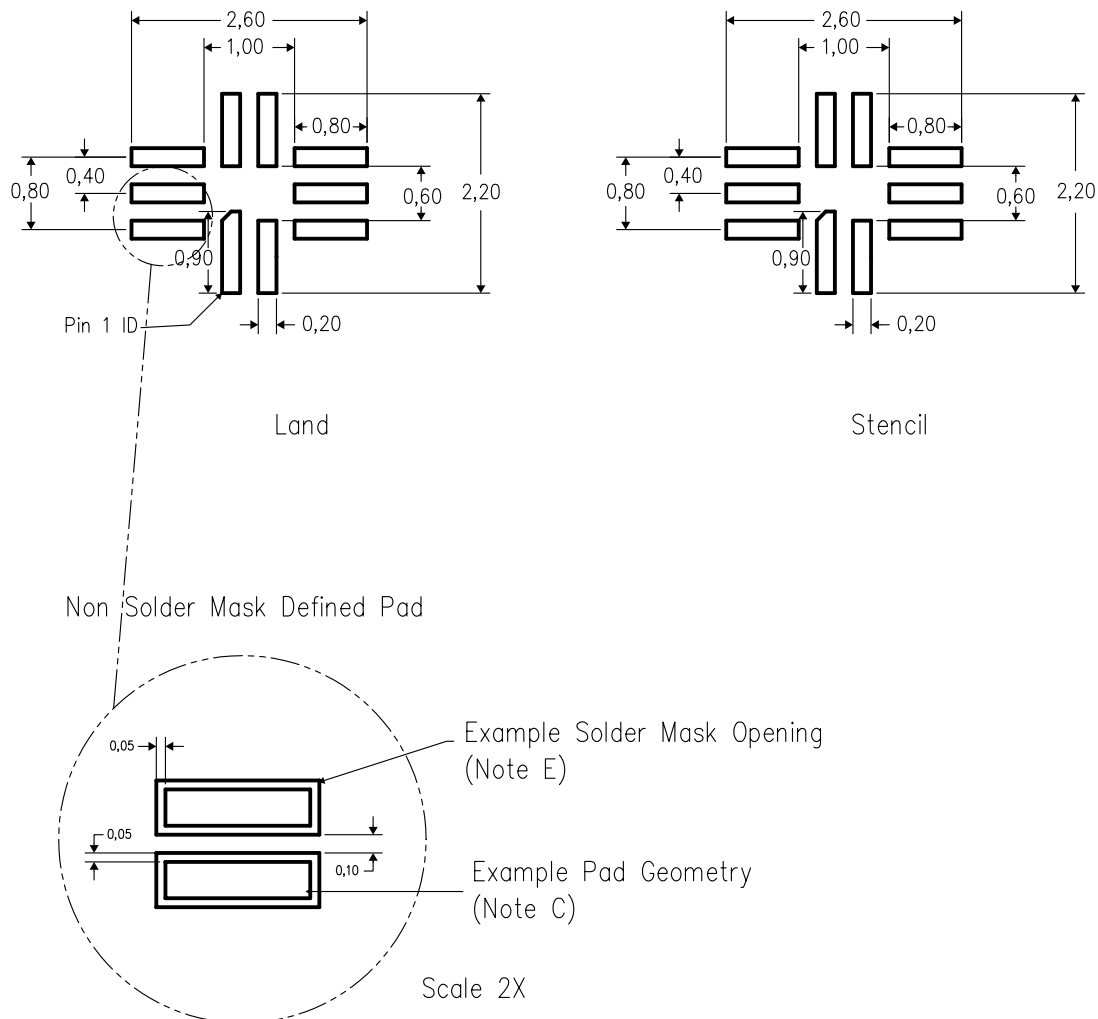
4208245/A 10/06

NOTES: A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Publication IPC−7351 is recommended for alternate designs.

D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
E. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.

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